IONIZED DOSE TESTING OF COMMERCIAL DC|DC BUCK CONVERTERS FOR ePIC

July 30th 2024, BNL Gamma Ray Facility

Presentation for DAQ & Electronics

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With Contributions from Gerard Visser, IU James Kierstead, BNL (Instrumentation Division)

Radiation Type	Facility	Comments
⁶⁰ Co	BNL (SSIF)	5k rads/ hour
64 MeV proton	UC Davis Previous testing for reference	120k rads/ hour Only LTC7890 same DUT from proton beam was used for TID testing at BNL. All other DUTs are new but same PN was tested at UC Davis.

Tested Devices

Part Number	Description	Package	DUT condition Resistor Loads Ambient Temperature ~ 21°C
LTC 3600	15V, 1.5A DC buck converter 200kHz to 4MHz	3x3mm DFN	V _{IN} : 14V Load: 1.5Ω V _{OUT} : 1.8V P _{OUT} : 2.16W Fsw: 1MHz
LTC 3626	20V, 2.5A DC buck converter 500KHz to 3MHz	4x3mm QFN	V _{IN} : 15V Load: 1.5Ω V _{OUT} : 1.8V P _{OUT} : 2.16W Fsw: 1MhZ
LTC 7151	20V, 15A DC buck converter 400KHz to 3MHz	5x4 QFN	V _{IN} : 12V Load: 0.68Ω V _{OUT} : 1.2V P _{OUT} : 2.12W Fsw: 1.5MHz
LTC 7890	2 channel synchronous GaN buck controller : Wide VIN range: 4 V to 100 V Wide output voltage range: 0.8 V ≤ VOUT ≤ 60 V 100KHz to 3MhZ	6x6QFN	V _{IN} : 12V Load: 0.6Ω / channel V _{OUT} : 1.2V P _{OUT} : 4.8W (ch1 + Ch2) Fsw: 2MhZ Previously irradiated at UC Davis (27K rad dose @ 120k / hour)

Cobalt 60 source inside

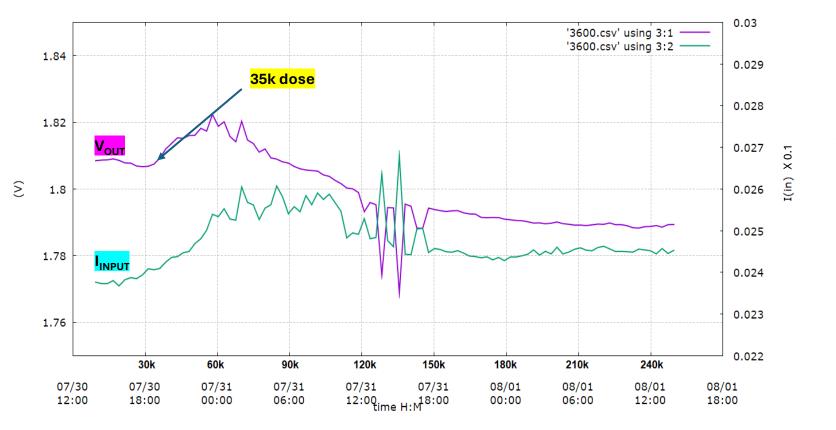


Source distant 6.0" (~5k rad/ hour)

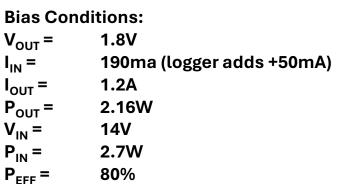


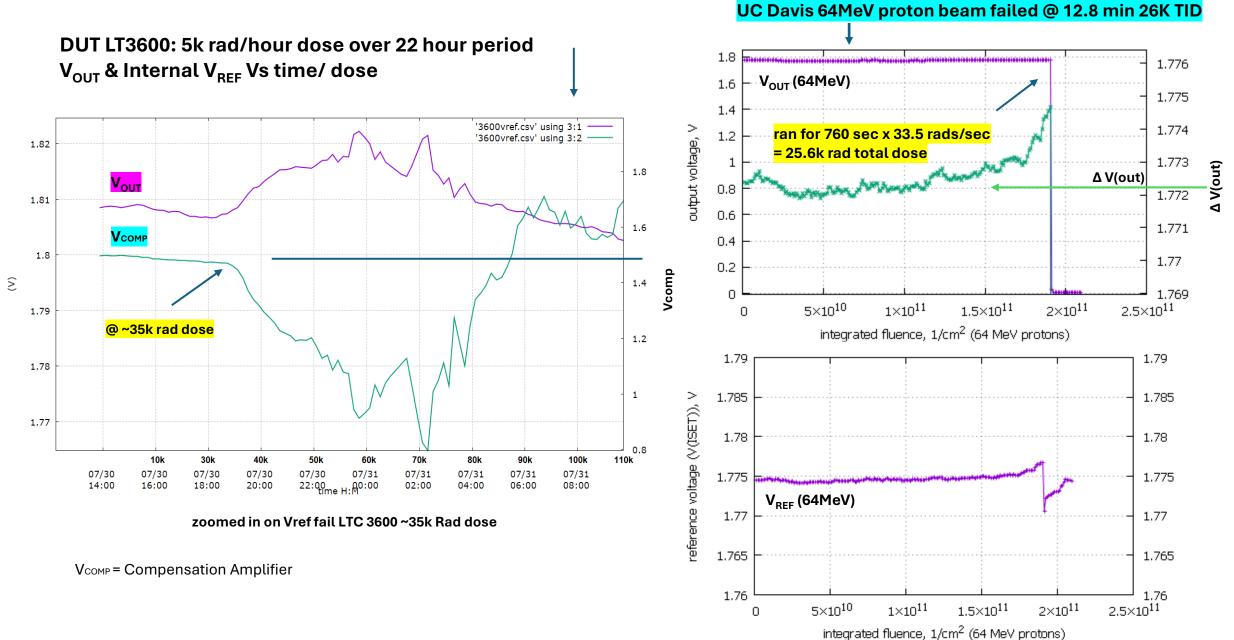
Two devices are tested at a time with both receiving the same dose



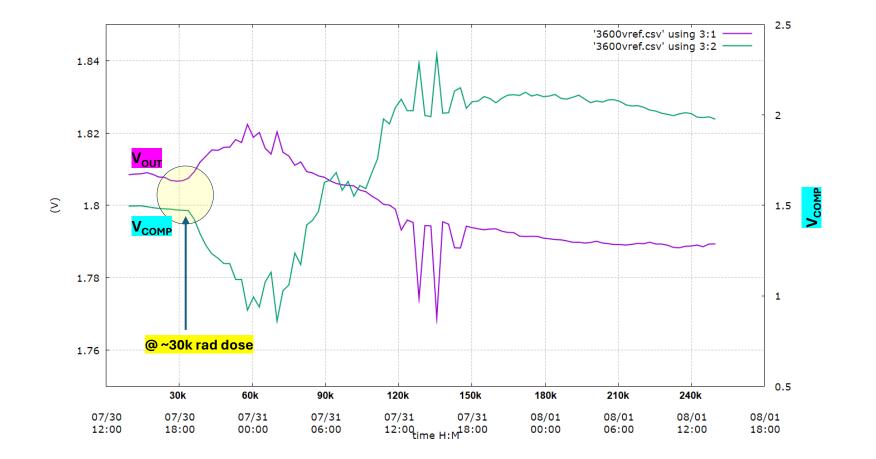


LT3600 DC:DC converter •1.5A Output Current •Adjustable Frequency: 200kHz to 4MHz •4V to 15V V_{IN} Range



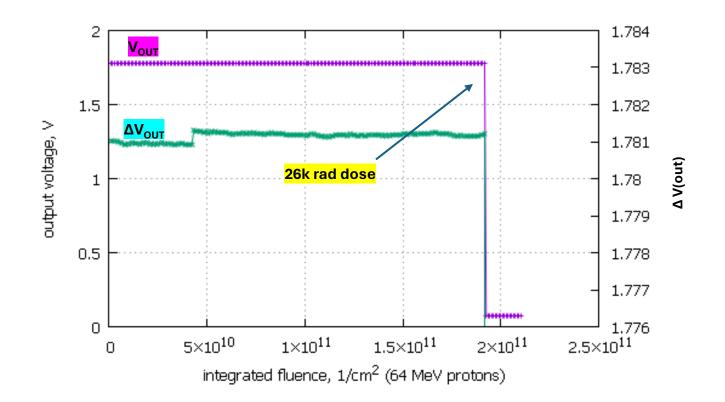


DUT LT3600: 5k rad/hour dose over 48 hour period V_{OUT} & Internal V_{REF} Vs time/ dose

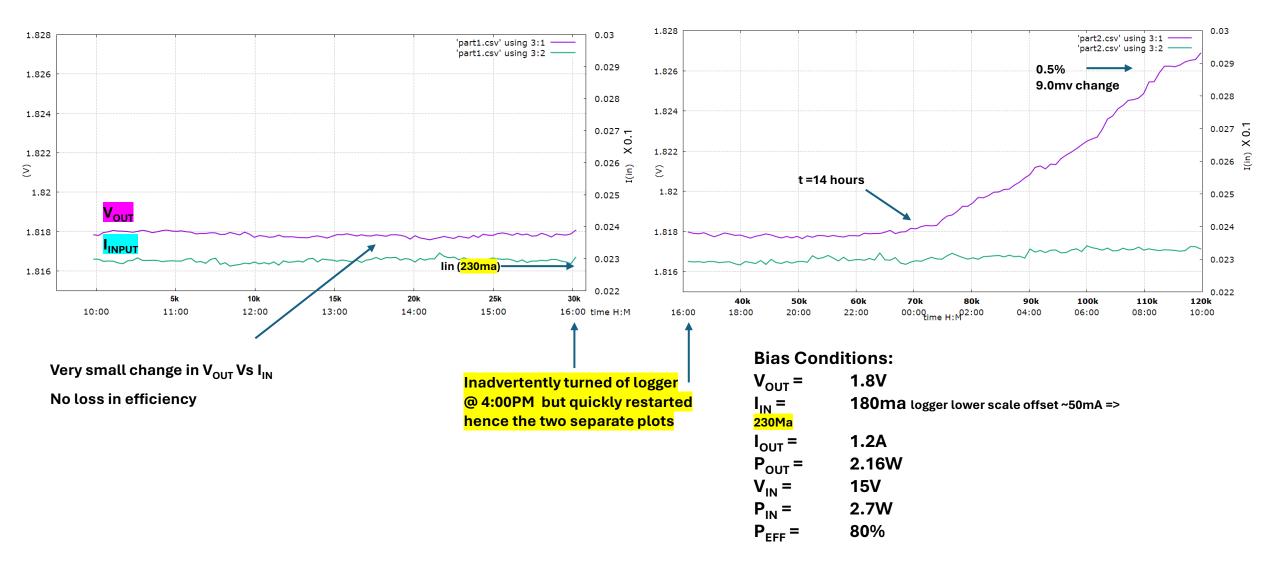


LTC3626 Irradiation Testing

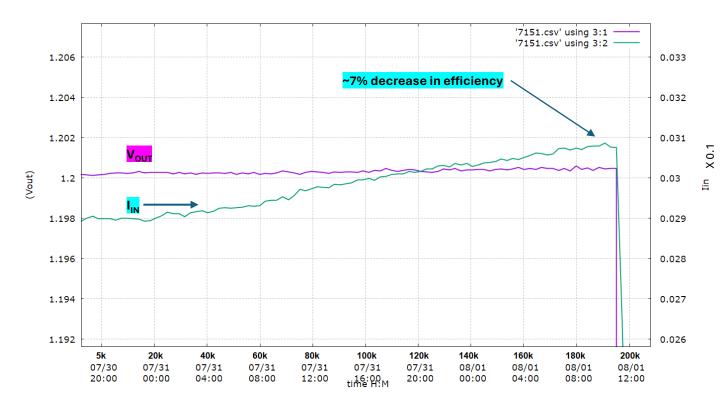
64MeV proton, UC DAVIS May 2024, 120k rads / hour



LTC3626 V_{OUT} with I_{IN} (load 1.5A) over a 24hour period (120k TID) $V_{OUT} \& I_{IN}$ Vs time/ dose



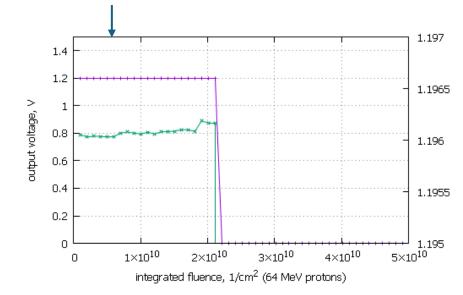
LTC7151 V_{OUT} with I_{IN} (load 1.8A) over a 40hour period (200k TID) V_{OUT} & I_{IN} Vs time/ dose



After a TID of ~190K rad, the DUT Vout drops out to 0 Volts

The DUT was powered 48 hours later and Vout and original efficiency are recovered.

UC Davis 64MeV proton beam: DUT failed at 2.2E10 neutrons /cm² & 3k rad dose

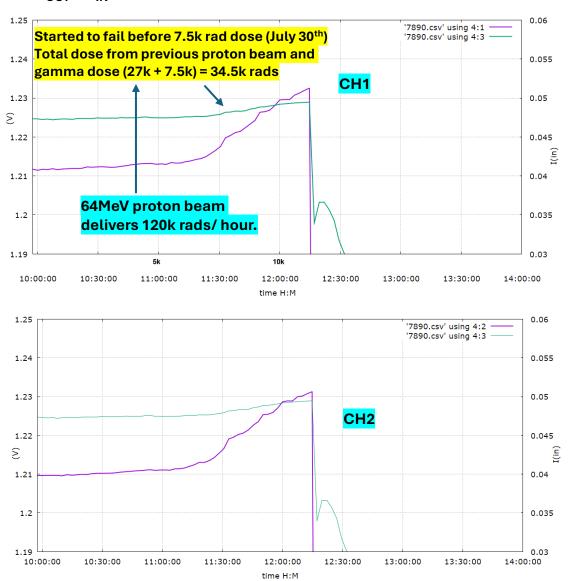


Bias Conditions:

V _{OUT} =	1.2V
I _{IN} =	250ma logger lower scale offset ~40mA
I _{OUT} =	1.8A
P _{OUT} =	2.16W
V _{IN} =	12.0V
P _{IN} =	3.00W
P _{EFF} =	70%

DUT: LTC7890 over a 24hour period (120k TID)

V_{OUT} & I_{IN} Vs time/ dose



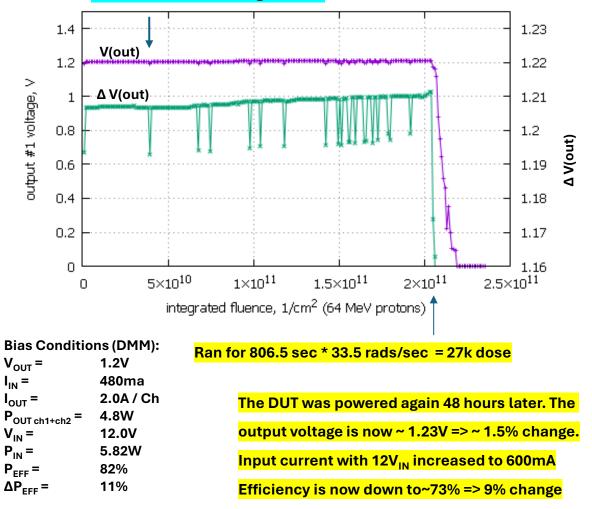
Same DUT from UC Davis 64MeV proton beam DUT recovered after serval days Before gamma facility test on July 30th, the DUT ran for 1 hour In lab

with no measurable degradation

I_{IN} =

V_{IN} =

P_{IN} =



Conclusions

LTC3600: Use at ePIC does not appear to be suitable

A different DUT was tested at UC Davis 64MeV proton beam in May 2024 (see slide# for beam conditions). The devices output failed at a fluence of 1.9E11 protons / cm² and an ionizing dose of ~26k rads. In that test the output dropped to 0 volts and the input current greatly increased. Several days later when the DUT was powered again, the input appears to be shorted.

A new DUT was tested in the gamma source @ 5k rads/ hour. The device seems to become unstable at 35k rad dose. Compared to the proton beam test the failure was not a complete dropout of Vout and shorted Vin. However, the failure of the DUT is evident by the steep change in internal VCOMP.

LTC3626: Device may be suitable for use at ePIC, pending our understanding of the dose rate effects & the displacement damage from the proton beam. Device failure under 64MeV proton beam may have been due to the higher dose rate of 120k rad/ hour Vs the gamma source 5k rad/ hour.

Device should be tested at Neutron facility.

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For the ionized rad exposure, the DUT showed no significant variation until Vout started to change after a 70k dose. From 70k rads to the end of the 24 hour test at 120k rads, V_{OUT} changed only ~9.0mV with no significant change in efficiency.

LTC7151: Devices failure under 64MeV proton beam may have been due to the higher dose rate of 120k rad/ hour Vs the gamma source 5k rad/ hour. Device should be tested at Neutron facility.

A different DUT was tested at UC Davis 64MeV proton beam in May 2024 (see slide# for beam conditions). The devices output failed at a fluence of 2.2E10 neutrons / cm² and an ionizing dose of ~3.0k rads. In that test the output dropped to 0 volts and the input current greatly increased. Several days later when the DUT was powered again, the input appears to be shorted.

For the ionized radiation exposure, the V_{OUT} remained stable with no measurable change up to ~190k rads. At 190k rad the devices output dropped to 0 volts and I_{IN} dropped to 0 Amps. At ~ 40k rads, the input current started to increase. From 40k rads to 190k rads. I_{IN} increased from ~290mA to ~310mA (efficiency dropped to 67% from 72%). After 48 hours the same DUT was powered and V_{OUT} is restored, and efficiency is ~70%.

LTC7890: Device may be suitable for use at ePIC pending our understanding of the dose rate effects.

Device should be tested at Neutron facility.

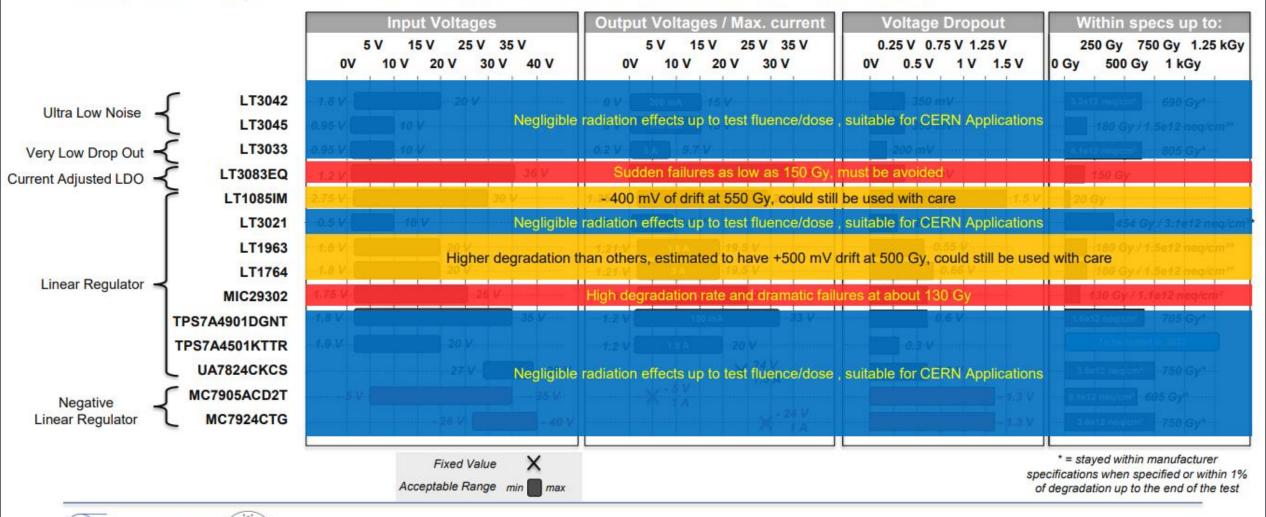
The same DUT was previously exposed in May 2024 at UC Davis 64MeV proton beam with a flux of 2.48E8 protons / CM² (120k rads/ hour). The DUT failed (Vout dropped to 0) at a fluence of ~2.0E11 p/ cm² and a dose of ~27k rads. After several days, the device was powered and Vout was recovered (~1.2V and efficiency was back to normal > %80). During the July 30th gamma test, Vout dropped to 0 volts after ~ 7.5k rad dose (total dose from proton beam was ~ 34.5 k rads).

Efficiency decreased from 82% to 73%.

ent File	Run Comment					
Riverside/UC-Riverside_5	-15-2024					
rrent Setup Pre-Ru		Pre-Run	lun		This Run	
eam Type: Proton eam Energy: 64 MeV arget: Silicon		Electrometer Range: 20 nA		Run Number:	3	
		FC Leakage: SEM Leakage:	-7.6e-13 ± 2.48e-13 1.33e-11 ± 1.17e-12	Device Name: Run Goal:	LTC3600 6.6e+11 p/cm ²	
						/dx (MeV·cm²/g): 8.334
atistics						
lapsed Time (s):	210.640		Average Beam Current (A):	2.01e-09		
Beam Current (A):	2.01e-09 ± 1.14e-10		Accumulated Dose (Rad):	7.05e+03		
Run Dose (Rad):	7.05e+03		Accumulated Fluence (p/cm ²):	5.28e+10		
Run Fluence (p/cm ²):	²): 5.28e+10		Dose Rate (rad/s):	33.5		
vg Beam Flux (p/cm²/s): 2.51e+08		Start Time of Last Run:	5/15/2024 10:18:05			
Run Progress						
				7% Paus	e Stop	
and the second s						
Actions						
New File	Close File Ru		un Settings Rat		About	
File Setup	View Printout		Leakage Start	Run	Exit	

Overview of Radiation-Tolerant Voltage Regulators

Are presented only the devices tested in representative LHC radiation environments (i.e. CHARM)



CERN